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Attorney Docket # 34250-54

Patent

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Mykhailo SHRIBAK et al.

Serial No.: 10/616,080

Filed: July 8, 2003

For: Retardance Measurement System and Method

Examiner: Nguyen, Tu T.
Group Art: 2877

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Name of applicant, assignee or Registered Representative



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August 7, 2006
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In compliance with the duty of disclosure under 37 C.F.R. §1.56 and in accordance with the practice under 37 C.F.R. §§1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO/SB/08a. Copies of the listed documents are also enclosed.

This information is being submitted subsequent to the later of three months after the filing date of the present application or the mailing of the first Office Action on the merits, but before the mailing of a final Action or the Notice of Allowance.

In accordance with 37 C.F.R §§1.97(g) and (h), the filing of this Information Disclosure Statement should not be construed as a representation that a search has been made or that information cited is, or is considered to be, material to patentability as defined in §1.56(b),

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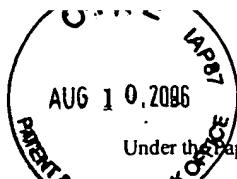
A check in the amount of \$180.00 in payment of the appropriate fee is enclosed. It is believed that no additional fees or charges are required at this time in connection with the present application. However, if any fees or charges are required at this time, they may be charged to our Patent and Trademark Office Deposit Account No. 03-2412.

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO/SB/08a be returned indicating that such information has been considered.

Respectfully submitted,
COHEN, PONTANI, LIEBERMAN & PAVANE LLP

By 
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Dated: August 7, 2006



AUG 10, 2006

PTO/SB/08A (04-03)

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT <small>(Use as many sheets as necessary)</small>		<i>Complete if Known</i>	
		Application Number	10/616,080
		Filing Date	July 8, 2003
		First Named Inventor	Mykhailo SHRIBAK
		Art Unit	2877
		Examiner Name	Nguyen, Tu T.
Sheet	1	of	2
		Attorney Docket Number	
		34250-54	

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT <small>(Use as many sheets as necessary)</small>		Application Number	10/616,080
Sheet 2 of 2		Filing Date	July 8, 2003
		First Named Inventor	Mykhailo SHRIBAK
		Art Unit	2877
		Examiner Name	Nguyen, Tu T.
		Attorney Docket Number	34250-54

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	AD	E. A. Patterson, W. Ji, and Z. Fwang, "On Image Analysis For Birefringence Measurements in Photoelasticity", <i>Optic Laser Engineering</i> , 28 , pp. 17-36, 1997	
	AE	S. Inoué, "A Method For Measuring Small Retardations of Structures in Living Cells", <i>Exp. Cell Res.</i> 2 , pp.513-517, 1951	
	AF	S. Inoué and R. Oldenbourg, <i>Microscopes</i> , in <i>Handbook of Optics</i> , M. Bass, Editor. 1995, McGraw-Hill, Inc.: New York. pp. 17.1-17.52	
	AG	M. Noguchi, T. Ishikawa, M. Ohno, and S. Tachihara, "Measurement of 2D Birefringence Distribution," in <i>International Symposium on Optical Fabrication, Testing, and Surface Evaluation</i> , Jumpei Tsujiuchi, ed., Proc. SPIE 1720 , 367-378, 1992	
	AH	Y. Otani, T. Shimada, T. Yoshizawa, "The Local-Sampling Phase Shifting Technique For Precise Two-Dimensional Birefringence Measurement", <i>Optical Review</i> , 1 (1), pp.103-106, 1994	
	AI	J. L. Pezzanitti, and R. A. Chipman, "Mueller Matrix Imaging Polarimetry", <i>Opt. Eng.</i> 34 (6), pp.1558-1568, 1995	
	AJ	Y. Zhu, T. Koyama, T. Takada, and Y. Murooka, "Two-Dimensional Measurement Technique For Birefringence Vector Distributions: Measurement Principle," <i>Appl. Opt.</i> 38 , pp. 2225-2231, 1999	
	AK	A. M. Glazer, J. G. Lewis, and W. Kaminsky, "An Automatic Optical Imaging System For Birefringent Media," <i>Proc. R. Soc. Lond. A</i> 452 , pp. 2751-2765, 1996	
	AL	M. I. Shribak "Autocollimating Detectors of Birefringence", in International Conference on Optical Inspection and Micromeasurements, Christophe Gorecki, Editors, Proc. SPIE 2782 , pp.805-813, 1996	
	AM	M. I. Shribak, Y. Otani and T. Yoshizawa, "Return-Path Polarimeter For Two Dimensional Birefringence Distribution Measurement", <i>Polarization: Measurement, Analysis, and Remote Sensing II</i> , Dennis H., Goldstein; and David B. Chenault; Eds. Proc., SPIE 3754 , pp. 144-149, 1999	

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